

Search Notes

Application/Control No.

10/727,567

Examiner

TUYEN T. NGUYEN

Applicant(s)/Patent under
Reexamination

ICHIKAWA ET AL.

Art Unit

2832

SEARCHED

Class	Subclass	Date	Examiner
336	65, 83, 178, 192, 198, 200,	3/17/2005	TTN
336	232	3/17/2005	TTN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR